

USB 3.1 ENGINEERING CHANGE NOTICE

Title: SSP System Jitter Budget
Applied to: USB_3_1r1.0_07_31_2013

Brief description of the functional changes:

Change to the 10Gbps system jitter budget. The change reduces the random jitter (RJ) budget for both transmitters and receivers from 18.4ps to 14.1ps each, and gives 6.1ps relief to the receiver deterministic jitter (DJ) budget.

Benefits as a result of the changes:

Reduces the design difficulty for SuperSpeed Gen 2 receivers by giving them more budget for deterministic jitter. The reduction in RJ is based upon comparison with other industry specs. For example, the jitter spec for PCIe4 and 10G KR are closer to 1ps RMS @ 1e-12BER. This ECR proposes to reduce the RJ budget from 18.4ps to 14.1ps at 1e-12BER (1.00ps RMS), which is consistent with those specs.

An assessment of the impact to the existing revision and systems that currently conform to the USB specification:

No existing systems exist.

An analysis of the hardware implications:

No existing products on the market. While this proposal is intended to make Gen 2 receivers easier to design, we acknowledge that there is potential impact to in-progress designs. The PHY development companies represented in the PHY WG (Intel, AMD, Synopsys) all support this change, recognizing the benefit to their design efforts.

An analysis of the software implications:

None

An analysis of the compliance testing implications:

The proposal results in changes to the Gen 2 eye mask for transmitter compliance and to the random jitter input for receiver jitter tolerance testing. Since the Gen 2 compliance program is not yet in place, these impacts are minimal as they will be incorporated into the CTS as we develop it.

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Actual Change

(a). From, in section 6.5.1, table 6-15, page 6-22

Table 6-1. Informative Jitter Budgeting at the Silicon Pads

Jitter Contribution (ps)	Gen 1 (5 GT/s)			Gen 2 (10 GT/s)		
	Rj ^{1,2}	Dj ³	Tj ⁴ at 10 ⁻¹²	Rj ^{1,2}	Dj ³	Tj ⁴ at 10 ⁻¹²
Tx ⁶	2.42	41	75	1.31	17	35.4
Media ⁵	2.13	45	75	0.00	36	36.0
Rx	2.42	57	91	1.31	21	39.4
Total:	4.03	143	200	1.85	74	100

Notes:

1. Rj is the sigma value assuming a Gaussian distribution.
2. Rj Total is computed as the Root Sum Square of the individual Rj components.
3. Dj budget is using the Dual Dirac method.
4. Tj at a 10⁻¹² BER is calculated as 14.068 * Rj + Dj.
5. The media budget includes the cancellation of ISI from the appropriate Rx equalization function.
6. Tx is measured after application of the JTF.

(a). To, in section 6.5.1, table 6-16, page 6-22

Table 6-2. Informative Jitter Budgeting at the Silicon Pads

Jitter Contribution (ps)	Gen 1 (5 GT/s)			Gen 2 (10 GT/s)		
	Rj ^{1,2}	Dj ³	Tj ⁴ at 10 ⁻¹²	Rj ^{1,2}	Dj ³	Tj ⁴ at 10 ⁻¹²
Tx ⁶	2.42	41	75	1.00	17	31.1
Media ⁵	2.13	45	75	0.00	36	36.0
Rx	2.42	57	91	1.00	27.1	41.2
Total:	4.03	143	200	1.41	80.1	100

Notes:

7. Rj is the sigma value assuming a Gaussian distribution.
8. Rj Total is computed as the Root Sum Square of the individual Rj components.
9. Dj budget is using the Dual Dirac method.
10. Tj at a 10⁻¹² BER is calculated as 14.068 * Rj + Dj.
11. The media budget includes the cancellation of ISI from the appropriate Rx equalization function.
12. Tx is measured after application of the JTF.

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(b). From, in section 6.7.3, table 6-19, page 6-32

Table 6-3. Normative Transmitter Eye Mask at Test Point TP1

Signal Characteristic	5GT/s			10GT/s			Units	Note
	Minimum	Nominal	Maximum	Minimum	Nominal	Maximum		
Eye Height	100		1200	70		1200	mV	2,4
Dj			0.43			0.530	UI	1,2,3
Rj			0.23			0.184	UI	1,2,3,5
Tj			0.66			0.714	UI	1,2,3

Notes:

1. Measured over 10^6 consecutive UI and extrapolated to 10^{-12} BER.
2. Measured after receiver equalization function.
3. Measured at end of reference channel and cables at TP1 in Figure 6-19.
4. The eye height is to be measured at the minimum opening over the range from the center of the eye ± 0.05 UI.
5. The Rj specification is calculated as 14.069 times the RMS random jitter for 10^{-12} BER.

(b). To, in section 6.7.3, table 6-19, page 6-32

Table 6-4. Normative Transmitter Eye Mask at Test Point TP1

Signal Characteristic	5GT/s			10GT/s			Units	Note
	Minimum	Nominal	Maximum	Minimum	Nominal	Maximum		
Eye Height	100		1200	70		1200	mV	2,4
Dj			0.43			0.530	UI	1,2,3
Rj			0.23			0.141	UI	1,2,3,5
Tj			0.66			0.671	UI	1,2,3

Notes:

1. Measured over 10^6 consecutive UI and extrapolated to 10^{-12} BER.
2. Measured after receiver equalization function.
3. Measured at end of reference channel and cables at TP1 in Figure 6-19.
4. The eye height is to be measured at the minimum opening over the range from the center of the eye ± 0.05 UI.
5. The Rj specification is calculated as 14.069 times the RMS random jitter for 10^{-12} BER.

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(c). From, in section 6.8.5, table 6-27, page 6-43

Table 6-5. Input Jitter Requirements for Rx Tolerance Testing

Symbol	Parameter	Gen 1 (5GT/s)	Gen 2 (10GT/s)	Units	Notes
f1	Tolerance corner	4.9	7.5	MHz	
J _{Rj}	Random Jitter	0.0121	0.01308	UI rms	1
J _{Rj_p-p}	Random Jitter peak- peak at 10 ⁻¹²	0.17	0.184	UI p-p	1,4
J _{Pj_500kHz}	Sinusoidal Jitter	2	4.76	UI p-p	1,2,3
J _{Pj_1MHz}	Sinusoidal Jitter	1	2.03	UI p-p	1,2,3
J _{Pj_2MHz}	Sinusoidal Jitter	0.5	0.87	UI p-p	1,2,3
J _{Pj_4MHz}	Sinusoidal Jitter	N/A	0.37	UI p-p	1,2,3
J _{Pj_f1}	Sinusoidal Jitter	0.2	0.17	UI p-p	1,2,3
J _{Pj_50MHz}	Sinusoidal Jitter	0.2	0.17	UI p-p	1,2,3
J _{Pj_100MHz}	Sinusoidal Jitter	N/A	0.17	UI p-p	1,2,3
V _{full_swing}	Transition bit differential voltage swing	0.75	0.8	V p-p	1
V _{EQ_level}	Non transition bit voltage (equalization)	-3	Preshoot=2.7 De-emphasis= -3.3	dB	1

Notes:

1. All parameters measured at TP1. The test point is shown in Figure 6-19.
2. Due to time limitations at compliance testing, only a subset of frequencies can be tested. However, the Rx is required to tolerate Pj at all frequencies between the compliance test points.
3. During the Rx tolerance test, SSC is generated by test equipment and present at all times. Each J_{Pj} source is then added and tested to the specification limit one at a time.
4. Random jitter is also present during the Rx tolerance test, though it is not shown in Figure 6-20.
5. The JTOL specs for Gen 2 comprehend jitter peaking with re-timers in the system and has a 25dB/decade slope.

(b). To, in section 6.8.5, table 6-27, page 6-43

Table 6-6. Input Jitter Requirements for Rx Tolerance Testing

Symbol	Parameter	Gen 1 (5GT/s)	Gen 2 (10GT/s)	Units	Notes
f1	Tolerance corner	4.9	7.5	MHz	
J _{Rj}	Random Jitter	0.0121	0.0100	UI rms	1
J _{Rj_p-p}	Random Jitter peak- peak at 10 ⁻¹²	0.17	0.184	UI p-p	1,4
J _{Pj_500kHz}	Sinusoidal Jitter	2	4.76	UI p-p	1,2,3
J _{Pj_1MHz}	Sinusoidal Jitter	1	2.03	UI p-p	1,2,3
J _{Pj_2MHz}	Sinusoidal Jitter	0.5	0.87	UI p-p	1,2,3
J _{Pj_4MHz}	Sinusoidal Jitter	N/A	0.37	UI p-p	1,2,3
J _{Pj_f1}	Sinusoidal Jitter	0.2	0.17	UI p-p	1,2,3
J _{Pj_50MHz}	Sinusoidal Jitter	0.2	0.17	UI p-p	1,2,3

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J _{Pj_100MHz}	Sinusoidal Jitter	N/A	0.17	UI p-p	1,2,3
V _{full_swing}	Transition bit differential voltage swing	0.75	0.8	V p-p	1
V _{EQ_level}	Non transition bit voltage (equalization)	-3	Preshoot=2.7 De-emphasis= -3.3	dB	1

Notes:

1. All parameters measured at TP1. The test point is shown in Figure 6-19.
 2. Due to time limitations at compliance testing, only a subset of frequencies can be tested. However, the Rx is required to tolerate Pj at all frequencies between the compliance test points.
 3. During the Rx tolerance test, SSC is generated by test equipment and present at all times. Each J_{Pj} source is then added and tested to the specification limit one at a time.
 4. Random jitter is also present during the Rx tolerance test, though it is not shown in Figure 6-20.
 5. The JTOL specs for Gen 2 comprehend jitter peaking with re-timers in the system and has a 25dB/decade slope.
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